


<b>Search Notes</b>  	<b>Application/Control No.</b>  10692314	<b>Applicant(s)/Patent Under Reexamination</b>  KRANZ ET AL.
	<b>Examiner</b>  Pardo, Thuy N	<b>Art Unit</b>  2168

SEARCHED			
Class	Subclass	Date	Examiner
707	2, 3, 6, 10	3/16/2007	TP
705	59	3/16/2007	TP
709	229	3/16/2007	TP
713	153, 189	3/16/2007	TP
707	102	12/6/2007	TP
705	57	12/6/2007	TP
713	165, 189	12/6/2007	TP
726	32	12/6/2007	TP
705	51, 59	5/25/2008	TP
713	189, 193	5/25/2008	TP

SEARCH NOTES		
Search Notes	Date	Examiner
WEST	3/16/2007	TP
WEST	12/6/2007	TP
WEST, NPL (IEEE, ACM)	5/25/2008	TP

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner